Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/774,573	NAGATA ET AL.	
Examiner	Art Unit	

Hien N. Nguyen

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	SEAR	CHED	
Class	Subclass	Date	Examiner
365	201	11/20/2005	HN
	201		
	230.03		
1	189.08	1	1
V	189.03	V	V

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
365	200	11/22/2005	HN
V	201	V	V
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(INCLUDING SE	CH NOTES ARCH STRATEGY)
	DATE	EXMR
EAST	11/20/2005	HN